## 2SK3396

### Silicon N-Channel Junction FET

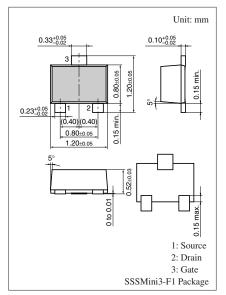
For impedance conversion in low frequency For infrared sensor

#### ■ Features

- Low gate-source cutoff current I<sub>GSS</sub>
- $\bullet$  Small capacitance of short-circuit forward transfer capacitance (common source)  $C_{iss}$ , short-circuit output capacitance (common source)  $C_{oss}$ , reverse transfer capacitance (common source)  $C_{rss}$

### ■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit	
Gate-drain voltage (Source open)	$V_{GDO}$	-40	V	
Gate-source voltage (Drain open)	$V_{GSO}$	-40	V	
Gate current	$I_G$	10	mA	
Drain current	$I_D$	1	mA	
Power dissipation	$P_{\mathrm{D}}$	100	mW	
Channel temperature	T <sub>ch</sub>	125	°C	
Storage temperature	T <sub>stg</sub>	-55 to +125	°C	

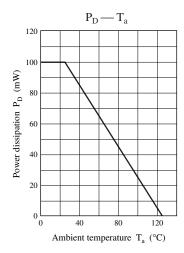


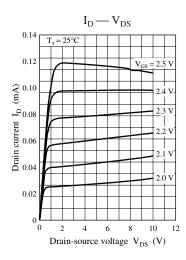
Marking Symbol: EB

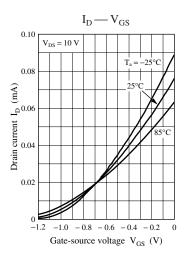
### ■ Electrical Characteristics $T_a = 25$ °C $\pm 3$ °C

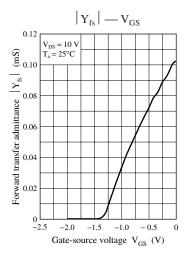
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Gate-drain surrender voltage	V <sub>GDS</sub>	$I_G = -10 \mu\text{A},  V_{DS} = 0$	-40			V
Drain-source cutoff current	$I_{DSS}$	$V_{DS} = 10 \text{ V}, V_{GS} = 0$	30		200	μΑ
Gate-source cutoff current	$I_{GSS}$	$V_{GS} = -20 \text{ V}, V_{DS} = 0$			- 0.5	nA
Forward transfer admittance	Y <sub>fs</sub>	$V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ kHz}$	0.05			mS
Gate-source cutoff voltage	V <sub>GSC</sub>	$V_{DS} = 10 \text{ V}, I_D = 1 \mu A$		-1.3	-3.0	V
Short-circuit forward transfer capacitance (Common source)	C <sub>iss</sub>	$V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$		1.0		pF
Short-circuit output capacitance (Common source)	C <sub>oss</sub>	$V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$		0.4		pF
Reverse transfer capacitance (Common source)	C <sub>rss</sub>	$V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$		0.4		pF

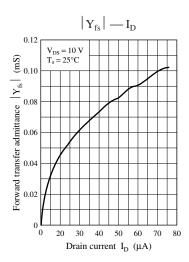
Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.











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